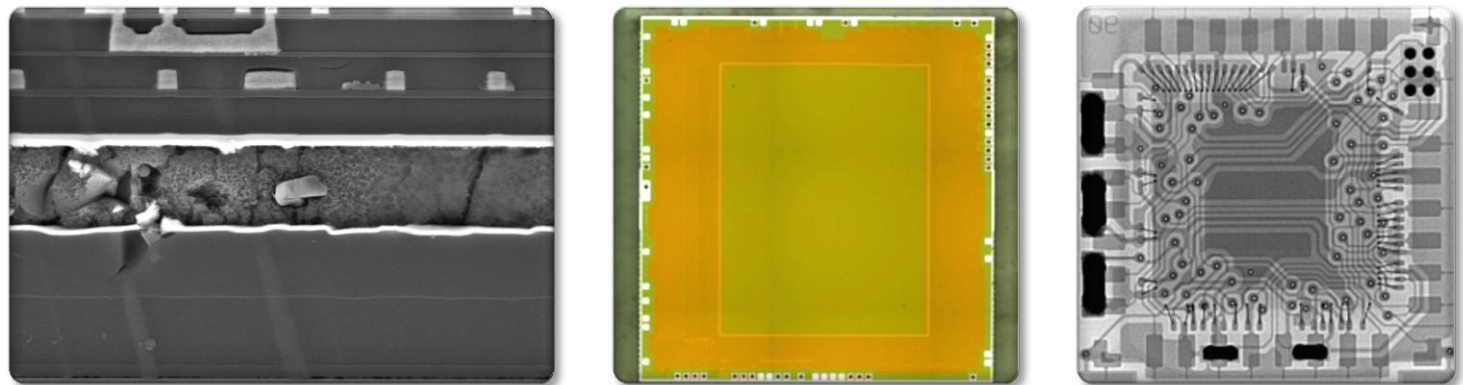


IMX219

Sony 8M Pixel CMOS Image Sensor



Product Analysis Report

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